PCT/GB 00/ 03242

10/049885 #2

INVESTOR IN PEOPLE

PATENTS • DESIGNS • COPYRIGHT • TRADE MARKS

The Patent Office

The Patent Office
Concept House
Cardiff Road
Newport
South Wales
NP10 8QQ

4

REC'D 04 OCT 2000

WIPO PCT

GB00/03242

I, the undersigned, being an officer duly authorised in accordance with Section 74(1) and (4) of the Deregulation & Contracting Out Act 1994, to sign and issue certificates on behalf of the Comptroller-General, hereby certify that annexed hereto is a true copy of the documents as originally filed in connection with the patent application identified therein.

In accordance with the Patents (Companies Re-registration) Rules 1982, if a company named in this certificate and any accompanying documents has re-registered under the Companies Act 1980 with the same name as that with which it was registered immediately before re-registration save for the substitution as, or inclusion as, the last part of the name of the words "public limited company" or their equivalents in Welsh, references to the name of the company in this certificate and any accompanying documents shall be treated as references to the name with which it is so re-registered.

In accordance with the rules, the words "public limited company" may be replaced by p.l.c., plc, P.L.C. or PLC.

Re-registration under the Companies Act does not constitute a new legal entity but merely subjects the company to certain additional company law rules.

Signed

Dated 22 SEP 2000

PRIORITY DOCUMENT
SUBMITTED OR TRANSMITTED IN
COMPLIANCE WITH
RULE 17.1(a) OR (b)

Patents Form 1/77

Patents Act 1977
(Rule 16)

THE PATENT OFFICE
21 AUG 1999
RECEIVED BY POST

The Patent Office

23AUG99 E471134-1 D02982
P01/7700 0.00 - 9919737.8

Request for grant of a patent

(See the notes on the back of this form. You can also get an explanatory leaflet from the Patent Office to help you fill in this form)

The Patent Office

Cardiff Road
Newport
Gwent NP9 1RH

1. Your reference

DWS/VV/P288GB

2. Patent application number
(The Patent Office will fill in this part)

21 AUG 1999 **9919737.8**

3. Full name, address and postcode of the or of each applicant *(underline all surnames)*

PRINTABLE FIELD EMITTERS LIMITED
Atlas Centre
Rutherford Appleton Laboratory
Chilton, DIDCOT
OX11 0QX
United Kingdom

Patents ADP number *(if you know it)*

If the applicant is a corporate body, give the country/state of its incorporation

United Kingdom

GB 6123600.1

4. Title of the invention

FIELD EMITTERS AND DEVICES

5. Name of your agent *(if you have one)*

"Address for service" in the United Kingdom to which all correspondence should be sent *(including the postcode)*

DAVID STANLEY INTELLECTUAL PROPERTY

Kings Court
12 King Street
LEEDS
LS1 2HL

Patents ADP number *(if you know it)*

06871289002

6. If you are declaring priority from one or more earlier patent applications, give the country and the date of filing of the or of each of these earlier applications and *(if you know it)* the or each application number

Country	Priority application number *(if you know it)*	Date of filing *(day / month / year)*

7. If this application is divided or otherwise derived from an earlier UK application, give the number and the filing date of the earlier application

Number of earlier application	Date of filing *(day / month / year)*

8. Is a statement of inventorship and of right to grant of a patent required in support of this request? *(Answer 'Yes' if:*

a) any applicant named in part 3 is not an inventor, or
b) there is an inventor who is not named as an applicant, or
c) any named applicant is a corporate body.
See note (d))

YES

Patents Form 1/77

Enter the number of sheets for any of the following items you are filing with this form. Do not count copies of the same document

Continuation sheets of this form	
Description	20
Claim(s)	5
Abstract	
Drawing(s)	7

10. If you are also filing any of the following, state how many against each item.

Priority documents	
Translations of priority documents	
Statement of inventorship and right to grant of a patent *(Patents Form 7/77)*	
Request for preliminary examination and search *(Patents Form 9/77)*	
Request for substantive examination *(Patents Form 10/77)*	
Any other documents *(please specify)*	Copy of GB 99 15633.3, Copy of GB 99 17882.4

11. I/We request the grant of a patent on the basis of this application.

Signature DAVID STANLEY INTELLECTUAL PROPERTY Date 20 August 1999

12. Name and daytime telephone number of person to contact in the United Kingdom David Stanley 01481 824411

Warning

After an application for a patent has been filed, the Comptroller of the Patent Office will consider whether publication or communication of the invention should be prohibited or restricted under Section 22 of the Patents Act 1977. You will be informed if it is necessary to prohibit or restrict your invention in this way. Furthermore, if you live in the United Kingdom, Section 23 of the Patents Act 1977 stops you from applying for a patent abroad without first getting written permission from the Patent Office unless an application has been filed at least 6 weeks beforehand in the United Kingdom for a patent for the same invention and either no direction prohibiting publication or communication has been given, or any such direction has been revoked.

Notes

a) *If you need help to fill in this form or you have any questions, please contact the Patent Office on 0645 500505.*

b) *Write your answers in capital letters using black ink or you may type them.*

c) *If there is not enough space for all the relevant details on any part of this form, please continue on a separate sheet of paper and write "see continuation sheet" in the relevant part(s). Any continuation sheet should be attached to this form.*

d) *If you have answered 'Yes' Patents Form 7/77 will need to be filed.*

e) *Once you have filled in the form you must remember to sign and date it.*

f) *For details of the fee and ways to pay please contact the Patent Office.*

FIELD EMITTERS AND DEVICES

This invention relates to field emission materials and devices, and is concerned particularly but not exclusively with methods of manufacturing addressable field electron emission cathode arrays. Preferred embodiments of the present invention aim to provide low manufacturing cost methods of fabricating multi-electrode control and focusing structures.

It has become clear to those skilled in the art that the key to practical field emission devices, particularly displays, lies in arrangements that permit the control of the emitted current with low voltages. At the present time, the majority of the art in this field relates to tip-based emitters - that is, structures that utilise atomically sharp micro-tips as the field emitting source.

There is considerable prior art relating to tip-based emitters. The main objective of workers in the art has been to place an electrode with an aperture (the gate) less than 1 micron away from each single emitting tip, so that the required high fields can by achieved using applied potentials of 100V or less - these emitters are termed gated arrays. The first practical realisation of this was described by C A Spindt, working at Stanford Research Institute in California *(J.Appl.Phys. 39,7, pp3504-3505, (1968))*. Spindt's arrays used molybdenum emitting tips which were produced, using a self masking technique, by vacuum evaporation of metal into cylindrical depressions in a SiO_2 layer on a Si substrate. Many variants and improvements on the basic Spindt technology are described in the scientific and patent literature.

An alternative important approach is the creation of gated arrays using silicon micro-engineering. Field electron emission displays utilising this technology are being manufactured at the present time, with interest by many organisations world-wide. Again many variants have been described.

A major problem with all tip-based emitting systems is their vulnerability to damage by ion bombardment, ohmic heating at high currents and the catastrophic damage produced by electrical breakdown in the device. Making large area devices is both difficult and costly. Furthermore, in order to get low control voltages, the basic emitting element, consisting of a tip and its associated gate aperture, must be approximately one micron or less in diameter. The creation of such structures requires semiconductor-type fabrication technology with its high associated cost structure. Moreover, when large areas are required, expensive and slow step and repeat equipment must be used.

In about 1985, it was discovered that thin films of diamond could be grown on heated substrates from a hydrogen-methane atmosphere, to provide broad area field emitters.

In 1988 S Bajic and R V Latham, *(Journal of Physics D Applied Physics, vol. 21 200-204 (1988))*, described a low-cost composite that created a high density of metal-insulator-metal-insulator-vacuum (MIMIV) emitting sites. The composite had conducting particles dispersed in an epoxy resin. The coating was applied to the surface by standard spin coating techniques.

Much later (1995) Tuck, Taylor and Latham *(GB 2 304 989)* improved the above MIMIV emitter by replacing the epoxy resin with an inorganic insulator that both improved stability and enabled it to be operated in sealed off vacuum devices.

The best examples of such broad-area emitters can produce usable electric currents at fields less than 10 $V\,m^{-1}$. In the context of this specification, a broad-area field emitter is any material that by virtue of its composition, micro-structure, work function or other property emits useable

electronic currents at macroscopic electrical fields that might be reasonably generated at a planar or near-planar surface - that is, without the use of atomically sharp micro-tips as emitting sites.

Electron optical analysis shows that the feature size required to control a broad-area emitter is nearly an order of magnitude larger than for a tip-based system. Zhu et al *(US Patent 5,283,501)* describes such structures with diamond-based emitters. Moyer *(US Patent 5,473,218)* claims an electron optical improvement in which a conducting layer sits upon the broad-area emitter to both prevent emission into the gate insulator and focus electrons through the gate aperture. The concept of such structures was not new and is electronoptically equivalent to arrangements that had been used in thermionic devices for many decades. For example Winsor *(US Patent 3,500,110)* described a shadow grid at cathode potential to prevent unwanted electrons intercepting a grid set at a potential positive with respect to the cathode. Somewhat later Miram *(US Patent 4,096,406)* improved upon this to produce a bonded grid structure in which the shadow grid and control grid are separated by a solid insulator and placed in contact with the cathode. Moyer's arrangement simply replaced the thermionic cathode in Miram's structure with an equivalent broad-area field emitter. However, such structures are useful, with the major challenge being methods of constructing them at low cost and over large areas. It is in this area that preferred embodiments of the present invention make a contribution to the art.

The applicants co-pending application *GB 2 330 687* describes a low manufacturing cost method of manufacturing a field emission display (FED) cathode plane using a broad-area field emitter. Figures 1a and 1b of the accompanying diagrammatic drawings show the structure of the cathode plane produced by this method in which a substrate 10 (usually glass) is

overlaid with cathode tracks 11, emitter layer 12, focus grid track 13, gate insulator 14 and gate tracks 15. All such tracks and layers are deposited by low resolution means e.g. printing. The upper surface is then coated with a resist layer which is exposed and developed to open apertures 16 in the resist to define the diameters of the emitter cells. A self aligning process using differential etches is then used to form the emitter cells and expose the emitter layer 12. Setting the gate electrode 15 positive with respect to the emitter layer 12 causes the emission of electrons 17 into the device.

Although this invention offers many advantages over the previous art it is best suited to emitter layers that have a surface roughness significantly less than the thickness of the gate insulator layer.

Many so-called broad-area emitters contain particles that either form the emitters themselves or are part of a composite emitter where one of their roles is to concentrate the macroscopic electric field. Examples of emitters of this type are described in the applicant's specifications *GB 2 332 089* and *GB 2 330 687*. Figure 2a of the accompanying diagrammatic drawings shows a typical structure of such an emitter as described in *GB 2 332 089* in which a substrate 210 (usually glass) has a conducting layer 211 coated with conducting particles 212 disposed within an insulating medium 213. On application of an electric field, conducting channels 214 form which transport and "heat" the electrons passing through them so that they are emitted at 215 into the vacuum. By a "channel" or "conducting channel" we mean a region of the insulator where its properties have been locally modified, usually by some forming process involving charge injection or heat. Such modification facilitates the injection of electrons from the conducting back contact into the insulator such that the electrons may move through it gaining energy and be emitted over or through the surface

potential barrier into the vacuum. In a crystalline solid the injection may be directly into the conduction band or, in the case of amorphous materials, at an energy level where hopping conduction is possible. For optimum performance the thickness of the insulator layers above and below the particle should be thin compared to the dimensions of the particle. Given this requirement, the emitter surface tends to have a roughness of the same order as the particle dimensions. Typical particle dimensions are in the few micron range.

Figure 2b of the accompanying diagrammatic drawings shows an exemplary case where an emitter with 2 micron particles is used in an 8 micron diameter emitter cell fabricated in a nominal 4 micron thick gate insulator. The layered structure is as follows: substrate 210 (usually glass), conducting cathode track 211, conducting particles 227 in insulator medium 228, focus grid track 222, gate insulator layer 223 and gate track 224. The emitter cell opening 225 just exposes a potential emitter 226. From a device operational perspective this example is satisfactory for use in say a FED, since the high electric field between the gate and the anode of the display will tend to straighten the electron trajectories.

Figure 2c of the accompanying diagrammatic drawings shows a far less satisfactory occurrence in which a large particle and its associated insulator coating 230 disrupt the gate structure to form two potential emitting sites. Emitting site 231 is benign since electrons 232 will only be emitted when the gate electrode 224 is in the "on" condition. Potential emitting site 233 presents a major problem since it could, under the influence of the DC field between the gate and anode, emit a continuous and uncontrolled current. In a display device this would result in a permanent bright spot and a scrapped panel.

It has occurred to us that it would be very desirable for such devices if the electrode and gate structures, which are made from materials that yield smooth films, could be fabricated first and the particle-containing emitter layer added as a final operation.

Moving now to Figure 3a of the accompanying diagrammatic drawings, Geis *et al* (*J. Vac. Sci. Technol. 8 14(3) May/June 1996*) describe a technique that involves forming a gated structure with a gate electrode 303 deposited on a silicon dioxide layer 302 that is grown on a conducting silicon substrate 300. Emitter cells 301 are formed by standard semiconductor fabrication processes. A paste 305 containing diamond particles is forced into the empty emitter cells 304 using a squeegee 306. The filled assembly is fired to 1080°C in a reducing atmosphere to evaporate the binder and form a compact 320, as shown in Figure 3b of the accompanying diagrammatic drawings, with good electrical and mechanical contact between the diamond and the silicon. Nickel may be added to the paste to facilitate electrical contact. The final assembly is plasma treated and then caesiated to reduce the electron affinity. Geis states that although this structure emits well, there is a very large gate current. Figure 3c of the accompanying diagrammatic drawings shows that this is likely to be caused by both current flow through the compact and emission direct to the gate 334 when voltages 332 and 331 are applied to the gate 303 and anode 330 respectively. Such spurious currents can be large compared to the desired emitted current 333. It is our view that this outcome is inevitable with this approach since the diamond particles tend to cling to the sidewalls of the emitter cells. Another problem is emitting debris 335 being left on top of the gate where it will produce uncontrolled currents 336. Passing mention is made of the use of spray or electrophoretic deposition but no details are given.

Danroc (*US Patent 5,836,796*) describes the use of electrophoresis to coat microtip emitters with fine diamond particle emitters to enhance emission. A metal additive deposited by electroplating is used to provide good electrical contact between the diamond and the metal microtip. Danroc is concerned only with microtip emitters.

Jin *(US Patent 5,811,916)* is concerned with field emission displays using a very specific type of diamond material. Jin mentions in passing the use of electrophoresis to dispose particles of this material, which is an emitting material *per se*, on a substrate, but no details are given.

Preferred embodiments of the present invention aim to provide improved field emitting structures wherein a particulate-containing composite field electron emitter is made *in situ* within a previously fabricated electrode structure. Said process preferably includes the use of electrophoresis to optimally locate the particles within the electrode structure. The emitter structures may be used in devices that include: field electron emission display panels; high power pulse devices such as electron MASERS and gyrotrons; crossed-field microwave tubes such as CFAs; linear beam tubes such as klystrons; flash x-ray tubes; triggered spark gaps and related devices; broad area x-ray sources for sterilisation; vacuum gauges; ion thrusters for space vehicles; particle accelerators; lamps; ozonisers; and plasma reactors.

According to one aspect of the present invention, there is provided A method of creating a composite broad area field electron emitter, comprising the steps of bringing together at least two constituents of the emitter on a substrate, in at least one region where the emitter is to be created, and processing said constituents to create said broad area field electron emitter in the or each said region.

Preferably, a plurality of said regions are defined by pre-formed emitter cells in a structure on said substrate, and said constituents are brought together in said cells.

Preferably, said constituents are dosed into said emitter cells using a squeegee or similar means.

Preferably, one of said constituents comprises a plurality of particles.

Preferably, electrophoresis is used to direct the particle constituent to desired locations from a suspension, which provides a fugitive vehicle for at least one of said constituents.

Preferably, a liquid component of the suspension has dissolved in it a precursor for one of said constituents, and said processing step comprises decomposition of said precursor by heat, ultra-violet light or other means to form that constituent.

Said precursor may be a sol-gel.

Said precursor may be a soluble polymer.

Preferably, one of said constituents is in the form of colloidal or fine particles that are carried in a suspension and in said processing step are sintered together by the action of heat to form a solid phase of the constituent.

Preferably, layers to promote electron emission are added during said processing step.

Preferably, said substrate has an electrically conductive surface and said field electron emission material comprises a plurality of electrically conductive particles, each with a layer of electrically insulating material

disposed in a first location between said conductive surface and said particle, and/or in a second location between said particle and the environment in which the field electron emission material is disposed, such that at least some of said particles form electron emission sites at said first and/or second locations.

Preferably, said electrically insulating material comprises silica and said electrically conductive particles comprise graphite.

Preferably, a resist or photoresist is used to mask areas where a field emitter layer is not required, and any unwanted residues are subsequently removed with the resist or photoresist, by a lift-off process.

Preferably, one of said constituents comprises an insulator which is formed by applying a metal that is subsequently oxidised.

Preferably, said metal is applied to conductive particles or conductive particles and a cathode track.

Preferably, said metal is applied by electroplating.

The invention extends to a field electron emission material formed by a method according to any of the preceding aspects of the invention.

In another aspect, the invention provides a field electron emission device comprising such a field electron emission material, and means for subjecting said material to an electric field in order to cause said material to emit electrons.

Such a device may comprise a substrate with an array of emitter patches of said field electron emission material, and control electrodes with

aligned arrays of apertures, which electrodes are supported above the emitter patches by insulating layers.

Preferably, said apertures are in the form of slots.

A device as above may comprise a plasma reactor, corona discharge device, silent discharge device, ozoniser, an electron source, electron gun, electron device, x-ray tube, vacuum gauge, gas filled device or ion thruster.

The field electron emission material may supply the total current for operation of the device.

The field electron emission material may supply a starting, triggering or priming current for the device.

A device as above may comprise a display device.

A device as above may comprise a lamp.

Said lamp may be substantially flat.

Said emitter may be connected to an electric driving means via a ballast resistor to limit current.

Said ballast resistor may be applied as a resistive pad under each said emitting patch.

Said emitter material and/or a phosphor may be coated upon one or more one-dimensional array of conductive tracks which are arranged to be addressed by electronic driving means so as to produce a scanning illuminated line.

Such a device may include said electronic driving means.

Said field emission material may be disposed in an environment which is gaseous, liquid, solid, or a vacuum.

A device as above may comprise a cathode which is optically translucent and is so arranged in relation to an anode that electrons emitted from the cathode impinge upon the anode to cause electro-luminescence at the anode, which electro-luminescence is visible through the optically translucent cathode.

It will be appreciated that the electrical terms "conducting" and "insulating" can be relative, depending upon the basis of their measurement. Semiconductors have useful conducting properties and, indeed, may be used in the present invention as conductors. In the context of this specification, an insulating material has an electrical resistivity at least 10^2 times (and preferably at least 10^3 or 10^4 times) that of a conducting material.

For a better understanding of the invention, and to show how embodiments of the same may be carried into effect, reference will now be made, by way of example, to the accompanying diagrammatic drawings, in which Figures 1 to 3 have already been mentioned above, and in which:

Figures 4a to 4d illustrate steps in one example of a method of creating a broad area field electron emitter;

Figures 5a to 5c illustrate steps in another example of a method of creating a broad area field electron emitter; and

Figures 6a to 6c illustrate examples of devices that utilise examples of broad area field electron emitters. Embodiments of this invention may have many applications and some of these will be described by way of the following examples. It should be understood that the following descriptions

are only illustrative of certain embodiments of the invention. Various alternatives and modifications can devised by those skilled in the art.

Example 1

We describe, by way of example, an emitter structure utilising a MIMIV emitter system as described in our *GB 2 304 989 B*. In this example, an emitter composite layer is assembled within an emitter cell in, say, a display, from its components. Emitters as described in our *GB 2 304 989 B* are routinely deposited on plane surfaces by spin coating using inks. These inks comprise an insulator precursor, such as a polymer or sol-gel; a solvent for the precursor; dispersants and surfactants plus the conducting particles. Following spin coating, the layer is heat treated to form the final layer. One such ink consists of a silica sol-gel dissolved in propan-2-ol with graphite particles dispersed to form a suspension. After spin coating a heat treatment profile to 450°C in air is used to cure the layer. The reader is directed to our co-pending application *GB 99 15633*, a copy of which is filed with the present application.

A suitable formulation for the ink is:

1) Sol-gel preparation

Tetraethyl orthosilicate (10 ml), and MOS grade propan-2-ol (47 ml) are mixed and cooled to 5-10°C with stirring at 1000 r.p.m. To this stirring mixture is then added a solution of concentrated nitric acid (0.10 g) in deionised water (2.5 g). After 2 hours, the mixture is transferred to a sealed container, and stored at 4°C in a refrigerator until required.

The proportion of MOS grade propan-2-ol is adjusted on test so that the number of particles and their ratio to insulator solid will be correct in the emitter cell that is used.

2) Dispersion Preparation

Nominal 6 micron graphite particles (0.150 g) and a sol-gel dispersion according to (1) above (9.850 g) previously filtered through a 0.2 micron filter are mixed, and ultrasonically agitated for 10 minutes using a high power ultrasonic probe. The sample is allowed to cool to room temperature and ultrasonically agitated for a further 10 minutes. This yields the required ink as a black suspension. The mixture is transferred to a sealed container and stored in a refrigerator at 4°C.

Figure 4a shows a substrate (usually glass 401); a cathode conducting track 402 (typically gold); an insulating layer 403 (usually glass); and a gate conductor 404 (typically gold). A photoresist layer 405 remains following the use of a self aligning process to form emitter cells 410. Such a structure may be fabricated by using the process that is described conceptually with reference to Figures 1a and 1b but missing out the emitter layer 12 and the focus grid layer 13. Full details of this process is described in our co-pending application *GB 2 330 687 A, to* which the reader's attention is directed. It will be clear to those skilled in the art how the processes therein may be adapted to fabricate the structure described in Figure 4a. However, the present invention is not limited to structures fabricated using this process. Other approaches, such as standard semiconductor fabrication processes, may be used.

Again referring to Figure 4a, an ink 407 comprising both particles 408 and a solution of insulator precursor is then applied to fill the empty emitter cells using a squeegee 406. During the squeegee process some unwanted particles with associated insulator precursor 409 will inevitably be deposited on the photoresist layer 405 covering the gate electrode.

At this point in the process we have a metered volume of ink in each emitter cell. The ink is formulated such that said volume of ink contains sufficient particles to lightly cover the base of the cell and sufficient insulator precursor to form an insulator layer of the required thickness once curing has taken place. If the curing process were performed now there would be, because of surface tension, a high probability that many particles will either form piles at the base of the cell or be fixed to its wall.

Figure 4b shows how this may problem may be avoided. Either following the squeegee process or before it is started, an electrical potential 411 is applied between the cathode track 402 and the gate electrode 404. The particles in suspension 413 will then be swept out of suspension and electrophoretically coated directly onto the cathode track 402. With insulating solvents this requires the cathode track to be biased positively with respect to the gate track. Electric fields in the range tens to hundreds of volts/cm are required. Any insulator precursor that adheres to the walls of the cell and is subsequently cured will be free of particles and thus not form emitting sites.

Alternative methods to a squeegee may be used to apply the suspension, such as K-coaters (wire roll) as supplied by R K Print-Coat Instruments Ltd, Litlington, Royston, Hertforshire, UK. Equally purpose-designed dispensers based, for example, on the extrusion of the suspension through slots may be utilised.

Following the electrophoretic deposition step the substrates are transferred to hotplates under the following conditions: a) 10 minutes at 50°C - measured surface temperature of hotplate; b) 10 minutes at 120°C - measured surface temperature of hotplate.

We are now at the stage shown in Figure 4c with a partially cured emitter layer 421 at the bottom of the cells and unwanted potential emitters 409 on the surface of the gate 405.

Moving now to Figure 4d the assembly 431 is transferred to an ultrasonic cleaner 432 filled with MOS grade acetone 433. The cleaner is operated for 10 - 20 seconds whilst agitating the assembly. During this period the photoresist layer 434 is removed together with unwanted debris 435 by a lift-off process, to provide a substantially planar outer surface 436 of the gate conductor 404.

The assembly is then rinsed on both sides with MOS grade acetone and again with MOS grade propan-2-ol.

Following the electrophoretic deposition step the substrates are transferred to hotplates under the following conditions: a) 10 minutes at 50°C - measured surface temperature of hotplate; b) 10 minutes at 120°C - measured surface temperature of hotplate.

The substrates are then transferred to an oven (air atmosphere) according to the following profile: ambient to 450°C at 10°C/min; isotherm at 450°C for 120 minutes; followed by cooling naturally to room temperature.

The resulting emitter structure is shown in Figure 4e

Example 2

Moving now to Figure 5 a more conventional approach to electrophoresis is used. A bath 602 contains a suspension of particles 605 in an insulator precursor solution 603. A formulation similar to that in Example 1 may be used but with the concentration of particles much

reduced. The substrate to be coated 600 (together with tracks, layers and emitter cells generally as described above with reference to Figure 4) is suspended in the bath and electrical connection 608 from one terminal of a power supply 604 is made to the cathode track. The gate electrode 607 is allowed to float electrically and is preferably covered with a layer of photoresist 609. A counter electrode 601 is connected to another terminal of power supply 604. On application of a voltage with a typical electric field in the range tens to hundreds of volts/cm the particles 605 are selectively electrophoretically coated onto the base of the emitter cells 606.

The substrate is now removed from the bath and drained, so that it is as shown in Figure 5b. Although this method can produce acceptable results, it can be seen that particles from the suspension 611 may remain in the volume of the emitter cell and, as shown in Figure 5c, remain in undesirable locations 620 after curing. Potentially emitting debris 610 on the surface of the gate would remain, if the photoresist 609 were not used or not subsequently removed.

The teaching herein concerning the assembly of a composite emitter *in situ* may be adapted to a wide range of situations. For example, as well as sol-gel and soluble insulator precursors (e.g. polymers), colloidal and fine particle suspensions may be used.

The insulator component may be formed by applying to the cathode track and particles (e.g. by electroplating) a metal that is subsequently oxidised.

The particles may also be electrophoretically deposited using an inert liquid medium and the insulator deposited in prior and/or subsequent process steps. Additional process steps may be introduced to add electron

emission enhancing interface and surface layers as described in our co-pending application *GB 99 17882.4*, a copy of which is filed with the present application

The field electron emission current available from improved emitter materials such as are disclosed above may be used in a wide range of devices including (amongst others): field electron emission display panels; lamps; high power pulse devices such as electron MASERS and gyrotrons; crossed-field microwave tubes such as CFAs; linear beam tubes such as klystrons; flash x-ray tubes; triggered spark gaps and related devices; broad area x-ray sources for sterilisation; vacuum gauges; ion thrusters for space vehicles and particle accelerators.

Examples of some of these devices are illustrated in Figures 6a, 6b and 6c.

Figure 6a shows an addressable gated cathode as might be used in a field emission display. The structure is formed of an insulating substrate 500, cathode tracks 501, emitter layer 502, focus grid layer 503 electrically connected to the cathode tracks, gate insulator 504, and gate tracks 505. The gate tracks and gate insulators are perforated with emitter cells 506. A negative bias on a selected cathode track and an associated positive bias on a gate track causes electrons 507 to be emitted towards an anode (not shown).

The reader is directed to our co-pending application *GB 2 330 687 (97 22258.2)* for further details of constructing Field Effect Devices.

The electrode tracks in each layer may be merged to form a controllable but non-addressable electron source that would find application in numerous devices.

Figure 6b shows how the addressable structure 510 described above may joined with a glass fritt seal 513 to a transparent anode plate 511 having upon it a phosphor screen 512. The space 514 between the plates is evacuated, to form a display.

Although a monochrome display has been described, for ease of illustration and explanation, it will be readily understood by those skilled in the art that a corresponding arrangement with a three-part pixel may be used to produce a colour display.

Figure 6c shows a flat lamp using one of the above-described materials. Such a lamp may be used to provide backlighting for liquid crystal displays, although this does not preclude other uses, such as room lighting.

The lamp comprises a cathode plate 520 upon which is deposited a conducting layer 521 and an emitting layer 522. Ballast layers as mentioned above (and as described in our other patent applications mentioned herein) may be used to improve the uniformity of emission. A transparent anode plate 523 has upon it a conducting layer 524 and a phosphor layer 525. A ring of glass fritt 526 seals and spaces the two plates. The interspace 527 is evacuated.

The operation and construction of such devices, which are only examples of many applications of embodiments of this invention, will readily be apparent to those skilled in the art. An important feature of preferred embodiments of the invention is the ability to print an electrode pattern before assembly of the emitter layer in situ, thus enabling complex multi-emitter patterns, such as those required for displays, to be created at modest cost. Furthermore, the ability to print enables low-cost substrate materials, such as glass to be used; whereas micro-engineered structures are typically

built on high-cost single crystal substrates. In the context of this specification, printing means a process that places or forms an emitting material in a defined pattern. Examples of suitable processes are (amongst others): screen printing, Xerography, photolithography, electrostatic deposition, spraying, ink jet printing and offset lithography.

Devices that embody the invention may be made in all sizes, large and small. This applies especially to displays, which may range from a single pixel device to a multi-pixel device, from miniature to macro-size displays.

Fugitive vehicles for the constituents of the emitter may be used in many examples.

In this specification, the verb "comprise" has its normal dictionary meaning, to denote non-exclusive inclusion. That is, use of the word "comprise" (or any of its derivatives) to include one feature or more, does not exclude the possibility of also including further features.

The reader's attention is directed to all papers and documents which are filed concurrently with or previous to this specification in connection with this application and which are open to public inspection with this specification, and the contents of all such papers and documents are incorporated herein by reference.

All of the features disclosed in this specification (including any accompanying claims, abstract and drawings), and/or all of the steps of any method or process so disclosed, may be combined in any combination, except combinations where at least some of such features and/or steps are mutually exclusive.

Each feature disclosed in this specification (including any

accompanying claims, abstract and drawings), may be replaced by alternative features serving the same, equivalent or similar purpose, unless expressly stated otherwise. Thus, unless expressly stated otherwise, each feature disclosed is one example only of a generic series of equivalent or similar features.

The invention is not restricted to the details of the foregoing embodiment(s). The invention extends to any novel one, or any novel combination, of the features disclosed in this specification (including any accompanying claims, abstract and drawings), or to any novel one, or any novel combination, of the steps of any method or process so disclosed.

CLAIMS

1. A method of creating a composite broad area field electron emitter, comprising the steps of bringing together at least two constituents of the emitter on a substrate, in at least one region where the emitter is to be created, and processing said constituents to create said broad area field electron emitter in the or each said region.

2. A method according to claim 1, wherein a plurality of said regions are defined by pre-formed emitter cells in a structure on said substrate, and said constituents are brought together in said cells.

3. A method according to claim 2, where said constituents are dosed into said emitter cells using a squeegee or similar means.

4. A method according to claim 1, 2 or 3, where one of said constituents comprises a plurality of particles.

5. A method according to claim 4, where electrophoresis is used to direct the particle constituent to desired locations from a suspension.

6. A method according to claim 5, where a liquid component of the suspension has dissolved in it a precursor for one of said constituents, and said processing step comprises decomposition of said precursor by heat, ultra-violet light or other means to form that constituent.

7. A method according to claim 6, where said precursor is a sol-gel.

8. A method according to claim 6, where said precursor is a soluble polymer.

9. A method according to any of claims 1 to 5, where one of said constituents is in the form of colloidal or fine particles that are carried in a suspension and in said processing step are sintered together by the action of heat to form a solid phase of the constituent.

10. A method according to any of claims 1 to 9, where layers to promote electron emission are added during said processing step.

11. A method according to any of the preceding claims, wherein said substrate has an electrically conductive surface and said field electron emission material comprises a plurality of electrically conductive particles, each with a layer of electrically insulating material disposed in a first location between said conductive surface and said particle, and/or in a second location between said particle and the environment in which the field electron emission material is disposed, such that at least some of said particles form electron emission sites at said first and/or second locations.

12. A method according to claim 11, where said electrically insulating material comprises silica and said electrically conductive particles comprise graphite.

13. A method according to any of the preceding claims, where a resist or photoresist is used to mask areas where a field emitter layer is not required, and any unwanted residues are subsequently removed with the resist or photoresist, by a lift-off process.

14. A method according to any of the preceding claims, where one of said constituents comprises an insulator which is formed by applying a metal that is subsequently oxidised.

15. A method according to claim 14, where said metal is applied to conductive particles or conductive particles and a cathode track.

16. A method according to claim 15, where said metal is applied by electroplating.

17. A method of forming a field electron emission material, substantially as hereinbefore described with reference to the accompanying drawings.

18. A field electron emission material formed by a method according to any of the preceding claims.

19. A field electron emission device comprising a field electron emission material according to claim 18, and means for subjecting said material to an electric field in order to cause said material to emit electrons.

20. A field electron emission device according to claim 19, comprising a substrate with an array of emitter patches of said field electron emission material, and control electrodes with aligned arrays of apertures, which electrodes are supported above the emitter patches by insulating layers.

21. A field electron emission device according to claim 20, wherein said apertures are in the form of slots.

22. A field electron emission device according to any of claims 19 to 21, comprising a plasma reactor, corona discharge device, silent discharge device, ozoniser, an electron source, electron gun, electron device, x-ray tube, vacuum gauge, gas filled device or ion thruster.

23. A field electron emission device according to any of claims 19 to 22, wherein the field electron emission material supplies the total current for operation of the device.

24. A field electron emission device according to any of claims 19 to 22, wherein the field electron emission material supplies a starting, triggering or priming current for the device.

25. A field electron emission device according to any of claims 19 to 22, comprising a display device.

26. A field electron emission device according to any of claims 19 to 22, comprising a lamp.

27. A field electron emission device according to claim 26, wherein said lamp is substantially flat.

28. A field electron emission device according to any of claims 19 to 27, wherein said emitter is connected to an electric driving means via a ballast resistor to limit current.

29. A field electron emission device according to claims 20 and 28, wherein said ballast resistor is applied as a resistive pad under each said emitting patch.

30. A field electron emission device according to any of claims 19 to 29, wherein said emitter material and/or a phosphor is/are coated upon one or more one-dimensional array of conductive tracks which are arranged to be addressed by electronic driving means so as to produce a scanning illuminated line.

31. A field electron emission device according to claim 30, including said electronic driving means.

32. A field electron emission device according to any of claims 19 to 31, wherein said field emission material is disposed in an environment which is gaseous, liquid, solid, or a vacuum.

33. A field electron emission device according to any of claims 19 to 33, comprising a cathode which is optically translucent and is so arranged in relation to an anode that electrons emitted from the cathode impinge upon the anode to cause electro-luminescence at the anode, which electro-luminescence is visible through the optically translucent cathode.

34. A field electron emission device, substantially as hereinbefore described with reference to the accompanying drawings.

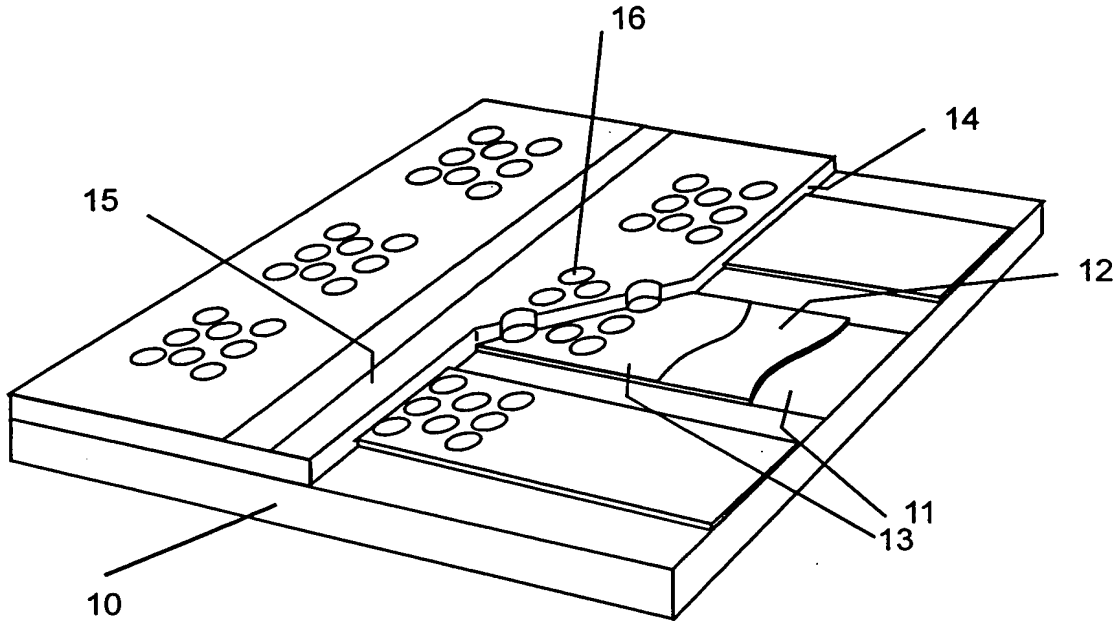

Figure 1a

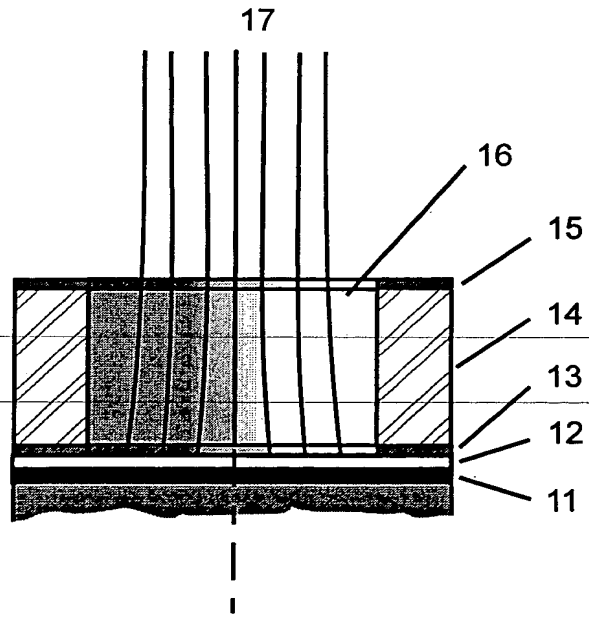

Figure 1b

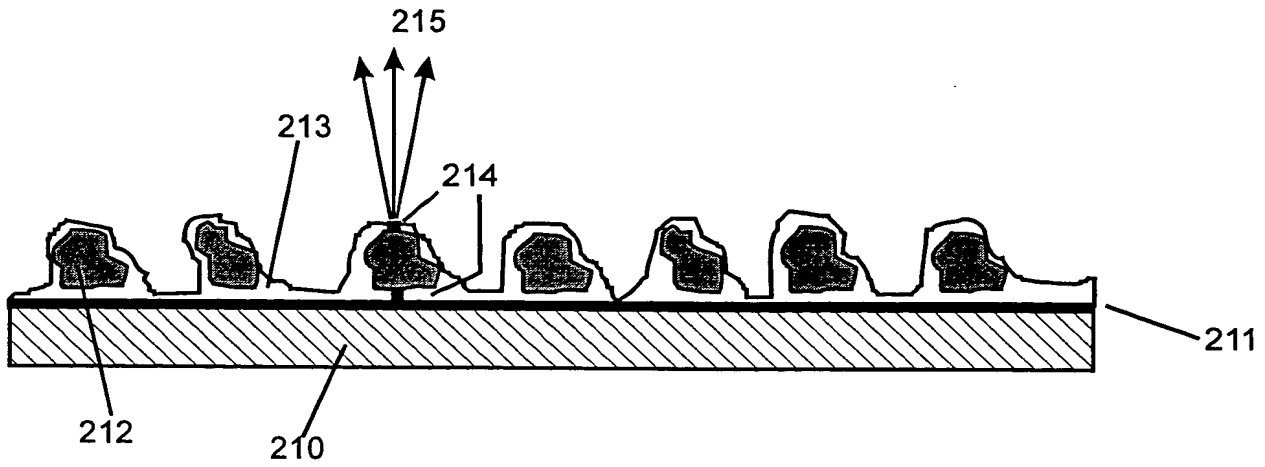

Figure 2a

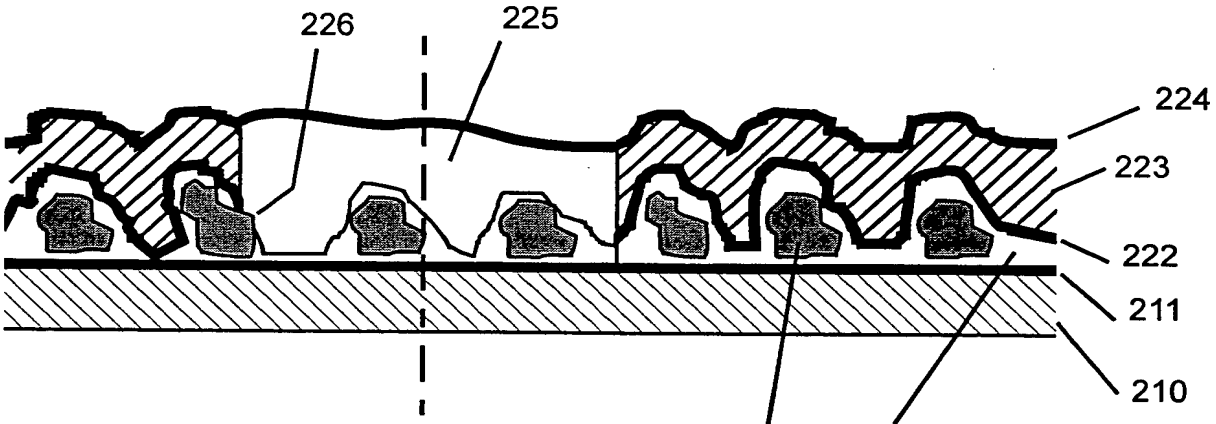

Figure 2b

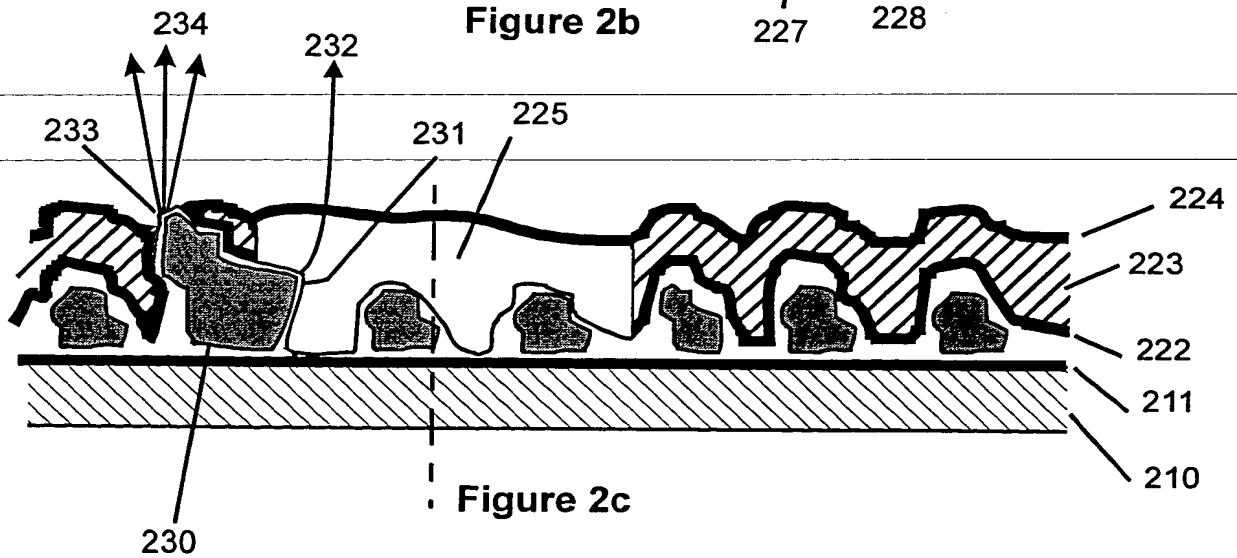

Figure 2c

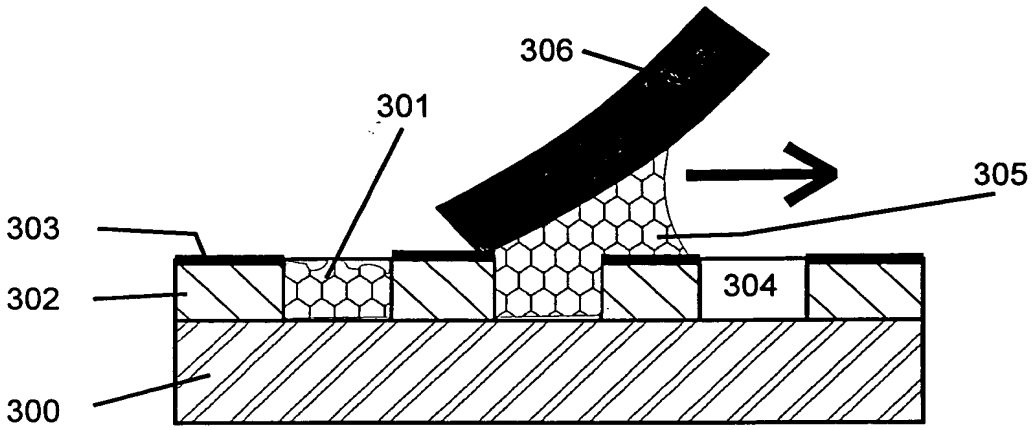

Figure 3a

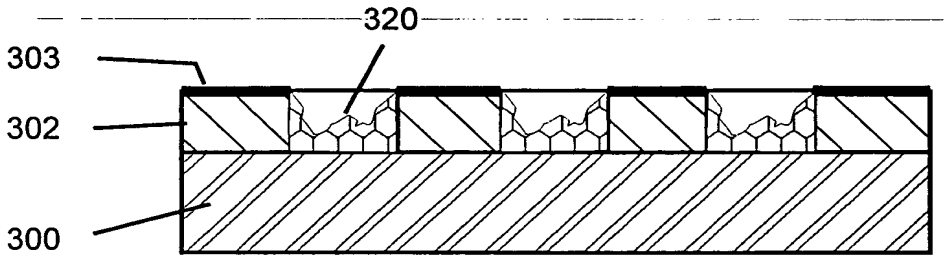

Figure 3b

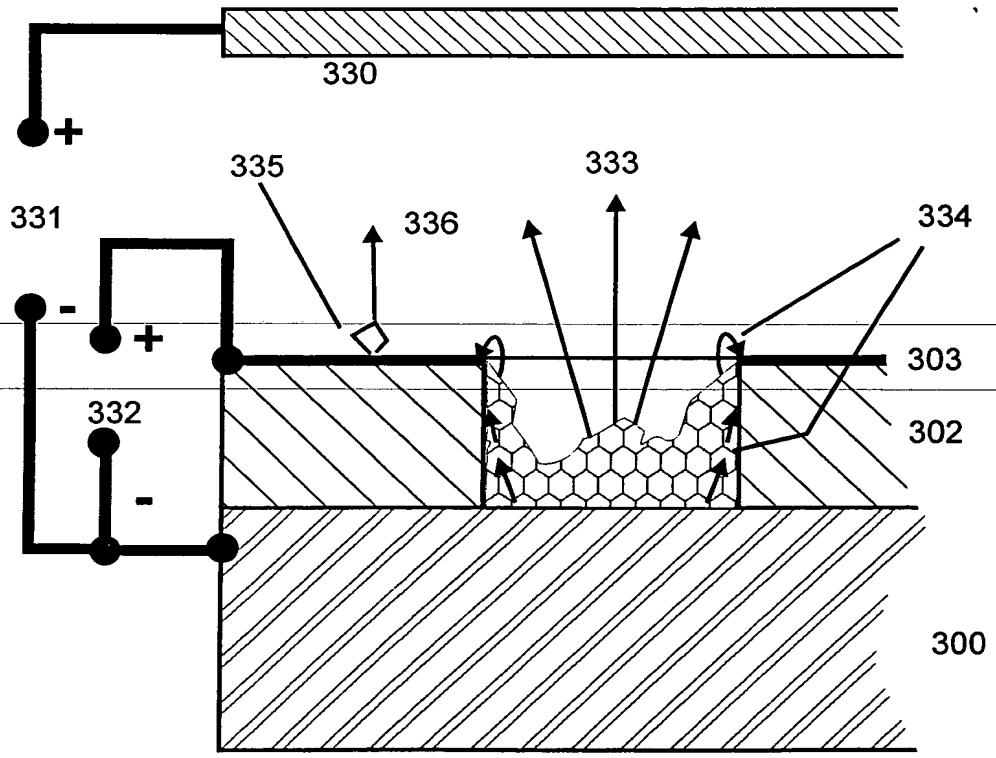

Figure 3c

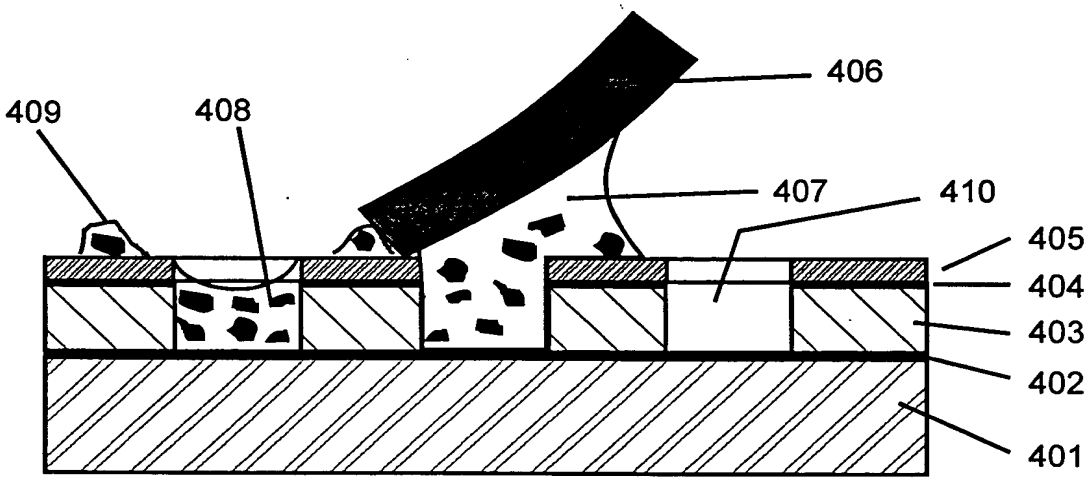

Figure 4a

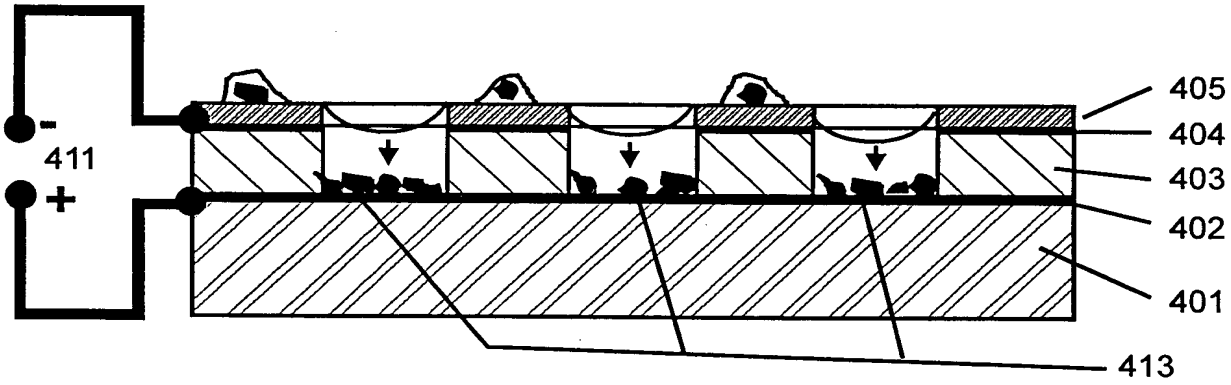

Figure 4b

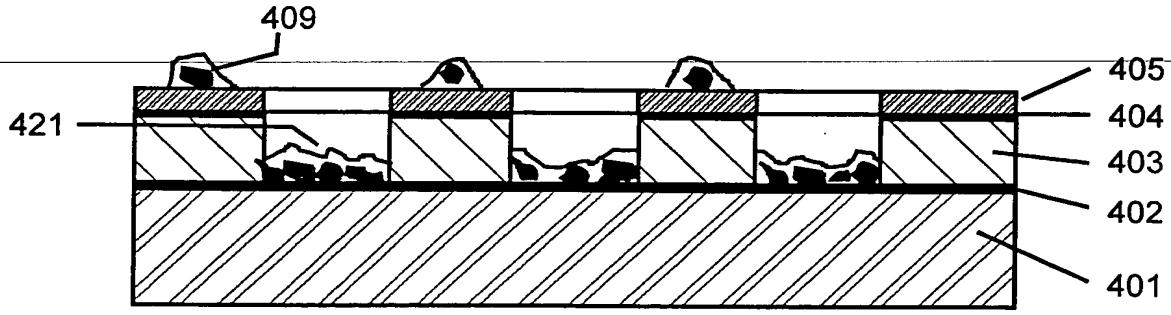

Figure 4c

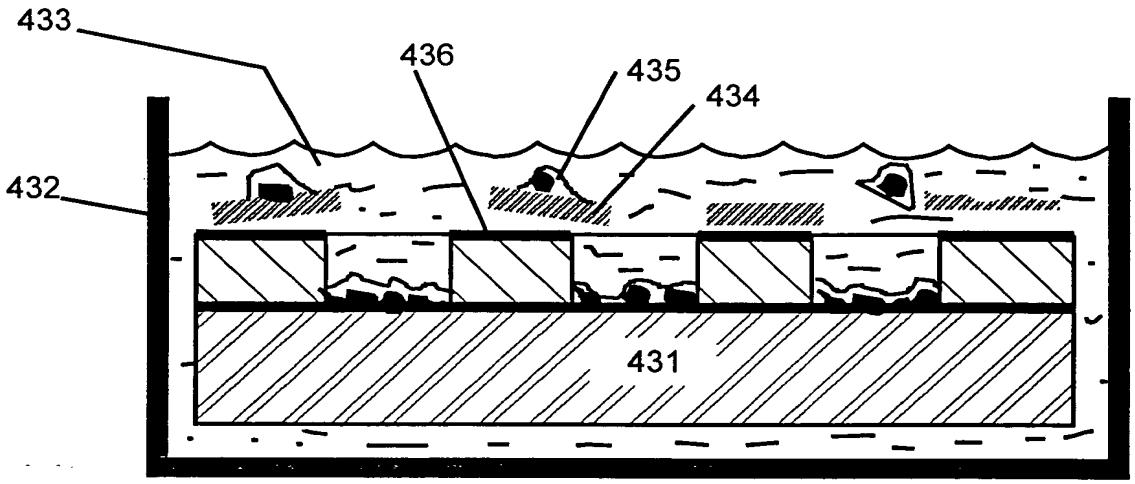

Figure 4d

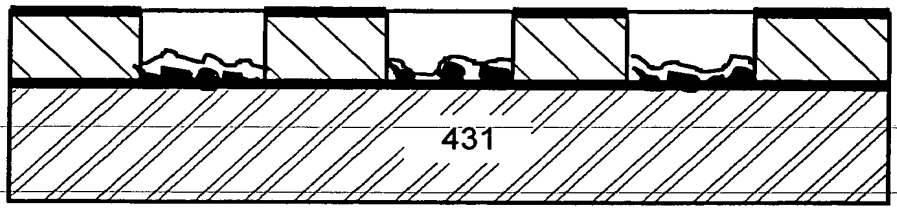

Figure 4e

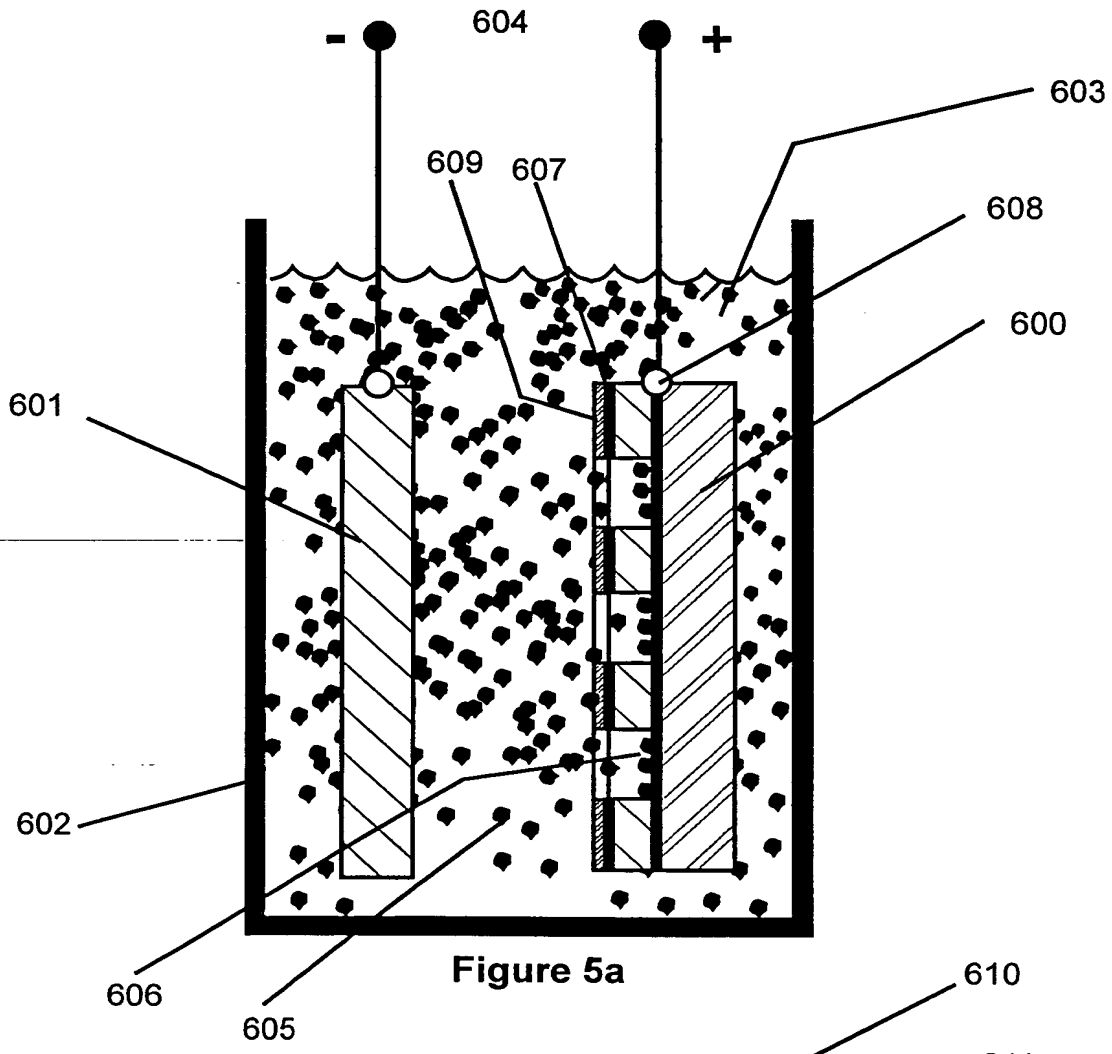

Figure 5a

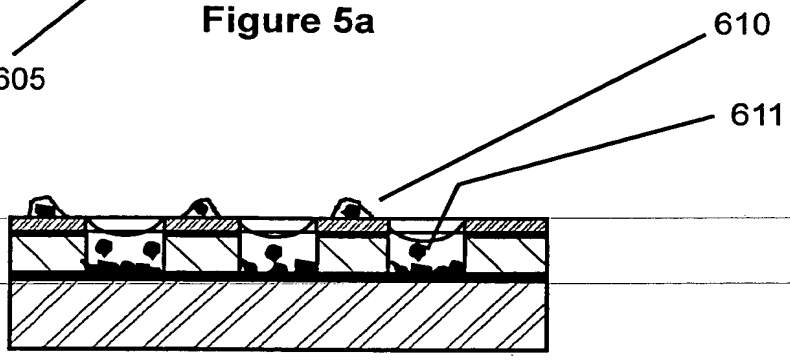

Figure 5b

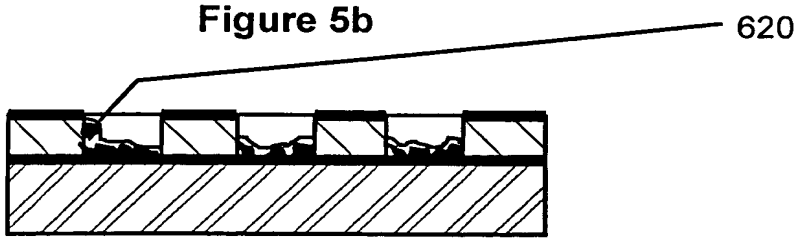

Figure 5c

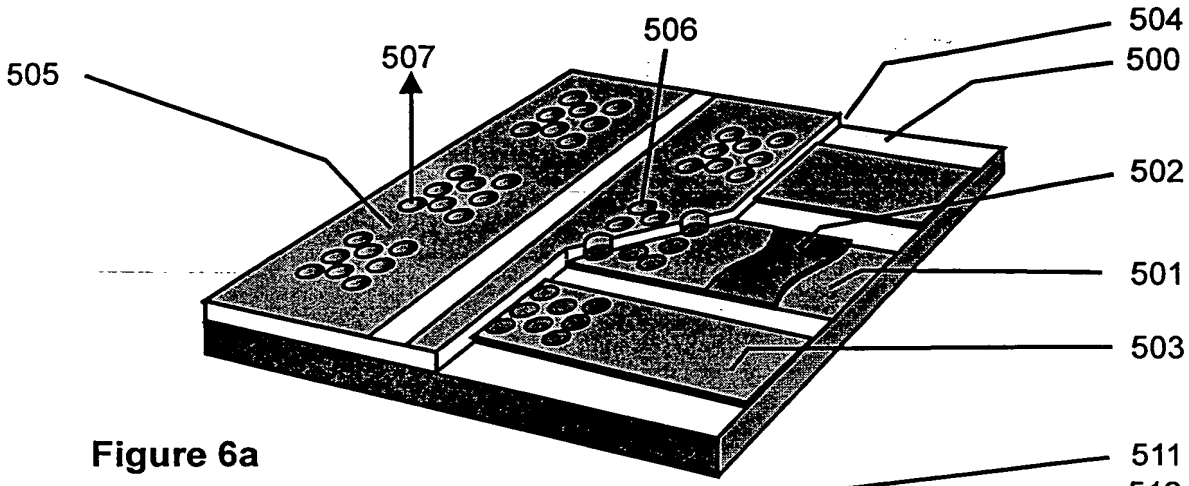

Figure 6a

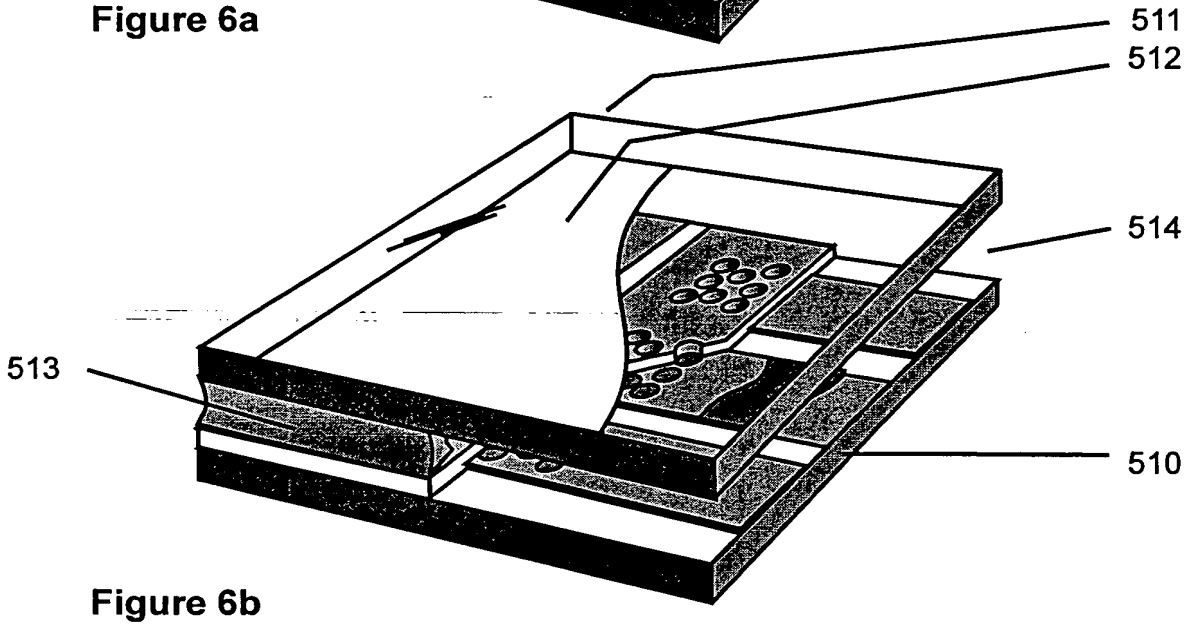

Figure 6b

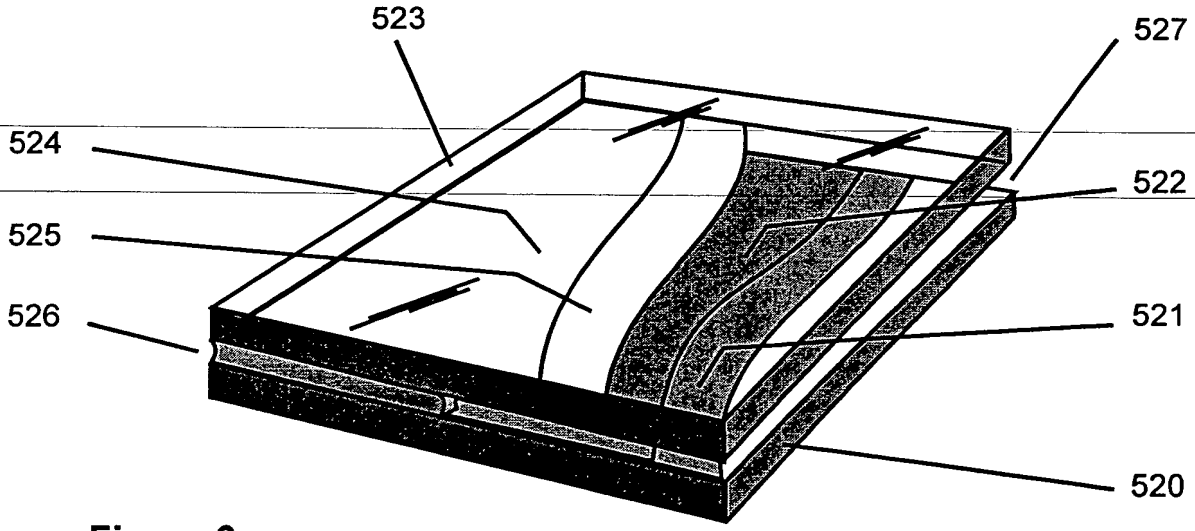

Figure 6c